

Flisom chooses LayTec for CIGS quality control

LayTec proudly announces that Flisom AG chooses LayTec to supply an advanced at-line mapping inspection tool for quality assurance in their CIGS (Cu (In,Ga) Se₂) thin film production line. The metrology tool will help Flisom to maintain maximum yield in manufacturing of light-weight flexible CIGS photovoltaic modules.

LayTec's stand-alone metrology system inspects film thickness, reflectivity, transmittance and sheet resistance by automated roll-to-roll mapping, whilst allowing flexible adaptation of the mapping mode. Hence, all key layers of the thin film stack will be monitored regarding layer quality and homogeneity. This will allow Flisom to implement an even tighter quality assurance scheme and to obtain further insights into the correlation of thin film parameters and device performance.



Flisom AG was founded in 2005 as a spin-off of the Solid-State Physics of the Swiss Federal Institute of Technology Zurich (ETH Zurich) – a scientific institution with global renown. For several years, the company remained in 'stealth mode', working closely with Empa to design and improve its core technology. The historic link with world-leading research institutions forms the basis of Flisom's identity, and the guarantee of continuous improvement of its cutting-edge technology. The company offers solar technology solutions for a range of applications in the buildings and transportation industries as well in specialized applications. For further information, visit. www.flisom.com.



LayTec develops and manufactures, among others, integrated in-line metrology for thin film PV deposition processes. Currently, the company has more than 2500 metrology systems installed worldwide and offers a global customer support and service network including local representations.

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